


<b>Search Notes</b>  	<b>Application/Control No.</b>  10642364	<b>Applicant(s)/Patent Under Reexamination</b>  JAYALEKSHMY ET AL.
	<b>Examiner</b>  Anthony Weier	<b>Art Unit</b>  1794

SEARCHED			
Class	Subclass	Date	Examiner
426	541, 629	3/6/08	AW

SEARCH NOTES		
Search Notes	Date	Examiner
PGPubText Search	3/6/08	AW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
426	541, 629	3/6/08	AW